

DYNAMIC BURN-IN METHOD AND APPARATUS

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ABSTRACT OF THE DISCLOSURE

10 In a dynamic burn-in apparatus wherein a signal
output from a signal generator is input to a
semiconductor device to be tested in the burn-in tank, a
converter is arranged at the output of the signal
generator. The converter increases, by N times, the
frequency of the signal output from a signal generator.
The signal having the increased frequency and output from
15 the converter, is input to the semiconductor device to be
tested in the burn-in tank when the burn-in is operated
at high-speed. The frequency of the signal is converted
to the higher frequency, and the signal having the higher
frequency is provided to the semiconductor device. As
20 the result, the burn-in can be done in a shorter time for
a high-speed sophisticated semiconductor device.